Notice of References Cited

Application/Control No.

10/710,309

Examiner

Daniel I. Walsh

Applicant(s)/Patent Under
Reexamination
BONALLE ET AL.

Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2001/0029493	10-2001	Pare et al.	705/64
*	В	US-5,764,789	06-1998	Pare et al.	382/115
*	C	US-2004/0084524	05-2004	Ramachandran, Natarajan	235/380
*	۵	US-2002/0174067	11-2002	Hoffman et al.	705/39
*	Е	US-2002/0062284	05-2002	KAWAN, JOSEPH C.	705/43
*	F	US-2001/0018660	08-2001	SEHR, RICHARD P.	705/5
*	G	US-2004/0155101	08-2004	Royer et al.	235/379
*	Η	US-2005/0098621	05-2005	de Sylva, Robert Francis	235/379
*	-	US-2001/0013551	08-2001	Ramachandran, Natarajan	235/472.02
*	7	US-6,925,439	08-2005	Pitroda, Satyan G.	705/1
	K	US-			
	اـ	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*	7 (1)	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	2					
	0					
	Р					
	Q					
	R					
***	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.